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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/792,292	FUJII ET AL.	
Examiner	Art Unit	
Adrian L. Kennedy	2121	

	SEARCHED		
Class	Subclass	Date	Examiner
706	59	8/5/2006	AK
706	8	8/5/2006	AK
706	50	8/5/2006	AK
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	CH NOTES ARCH STRATEGY)
	DATE	EXMR
PLUS Search	8/17/2006	AK
IEEE NPL Search	8/21/2006	AK
ACM NPL Search	8/21/2006	AK
EAST Keyword	8/17/2006	AK
EAST Keyword	8/18/2006	AK
EAST Keyword	8/21/2006	AK